

# Nyquist-Rate A/D Converters

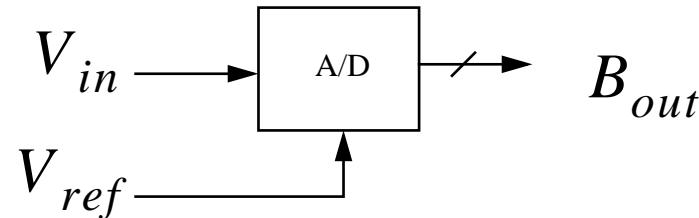
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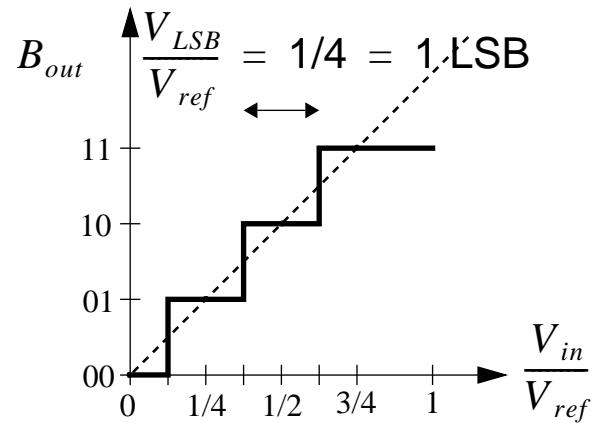
# A/D Converter Basics



$$V_{ref}(b_1 2^{-1} + b_2 2^{-2} + \dots + b_N 2^{-N}) = V_{in} \pm x$$

$$\text{where } \left( -\frac{1}{2} V_{LSB} < x < \frac{1}{2} V_{LSB} \right) \quad (1)$$

- ***Range of valid input values produce the same output signal — quantization error.***



# Analog to Digital Converters

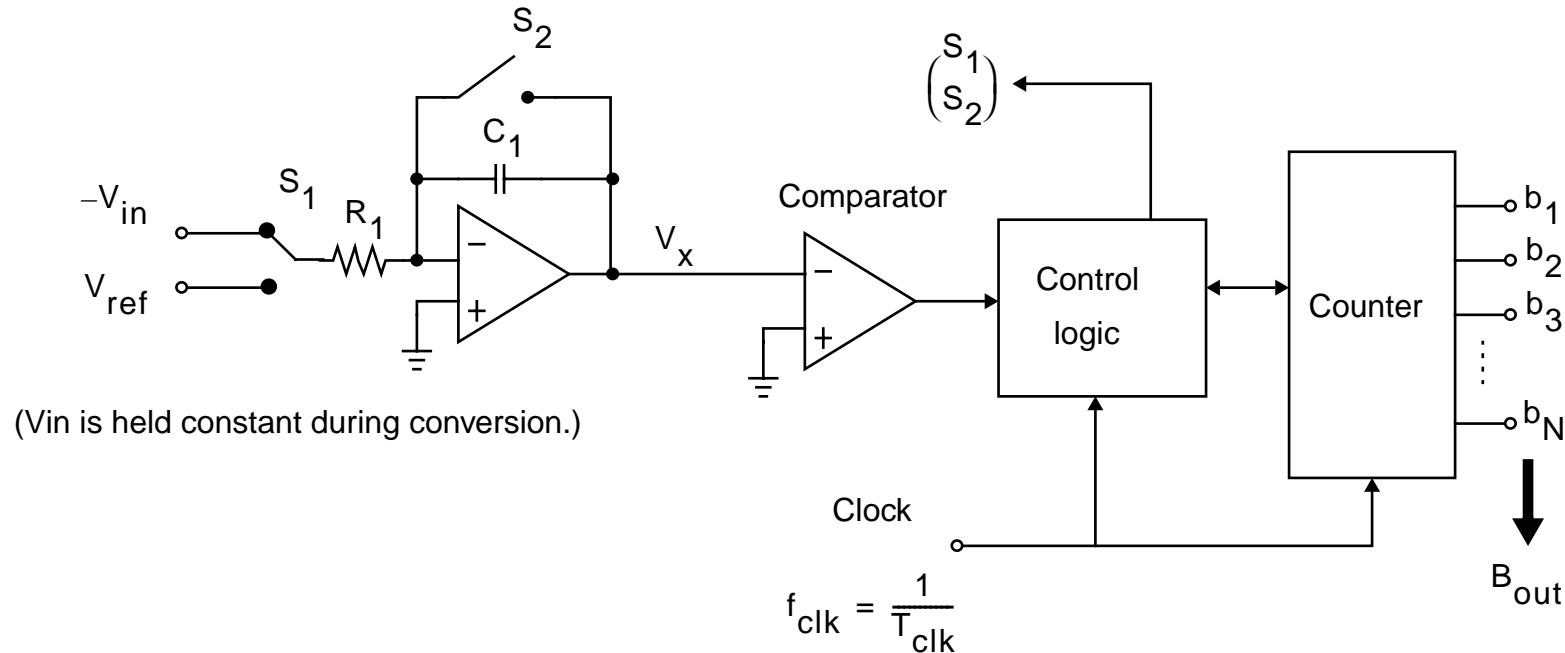
Low-to-Medium Speed, High Accuracy	Medium Speed, Medium Accuracy	High Speed, Low-to-Medium Accuracy
Integrating	Successive approximation	Flash
Oversampling (not Nyquist-rate)	Algorithmic	Two-step
		Interpolating
		Folding
		Pipelined
		Time-interleaved



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# Integrating Converters



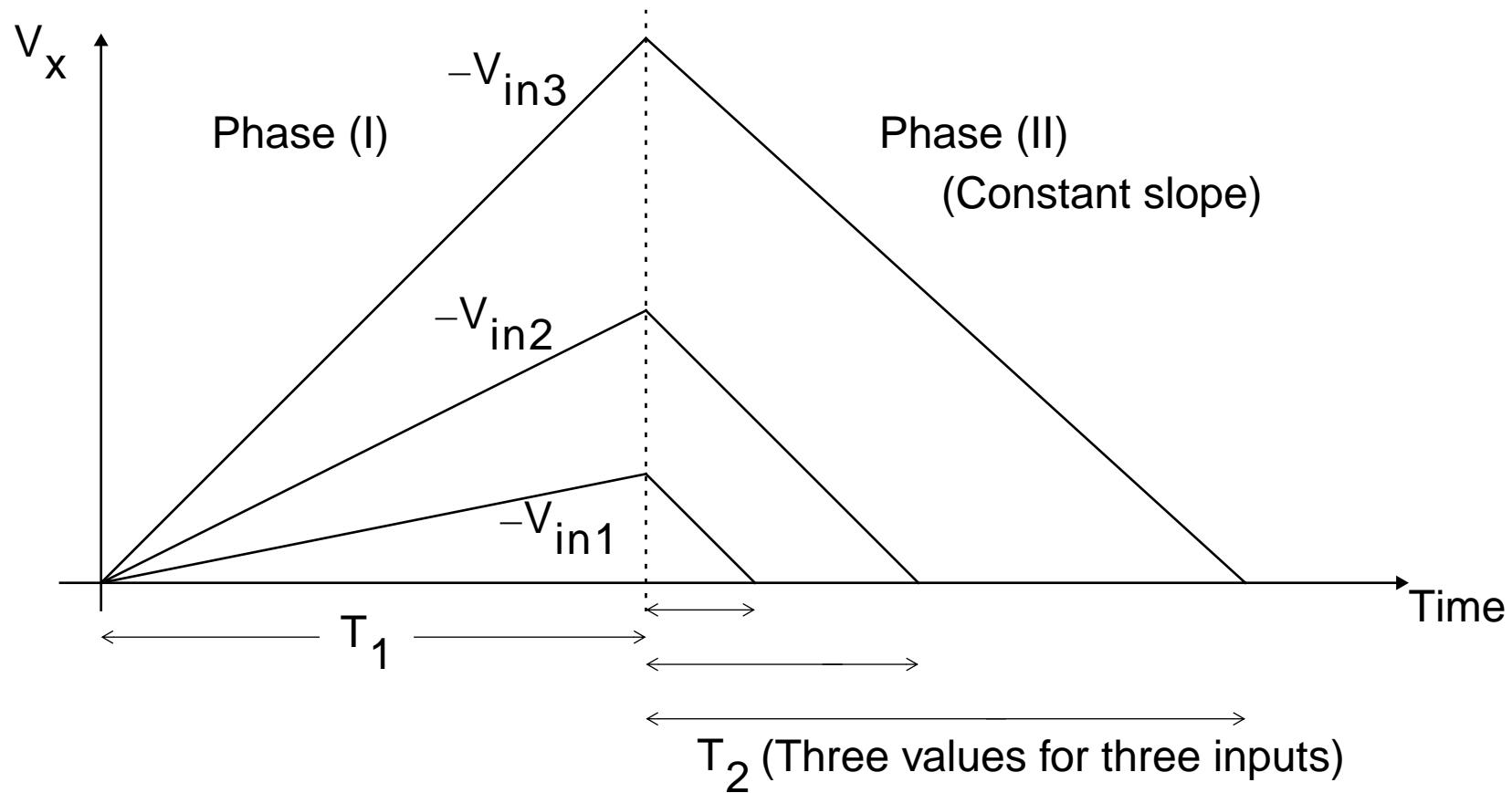
- Low offset and gain errors for low-speed applications
- Small amount of circuitry
- Conversion speed is  $2^{N+1}$  times  $1/T_{clk}$



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# Integrating Converters

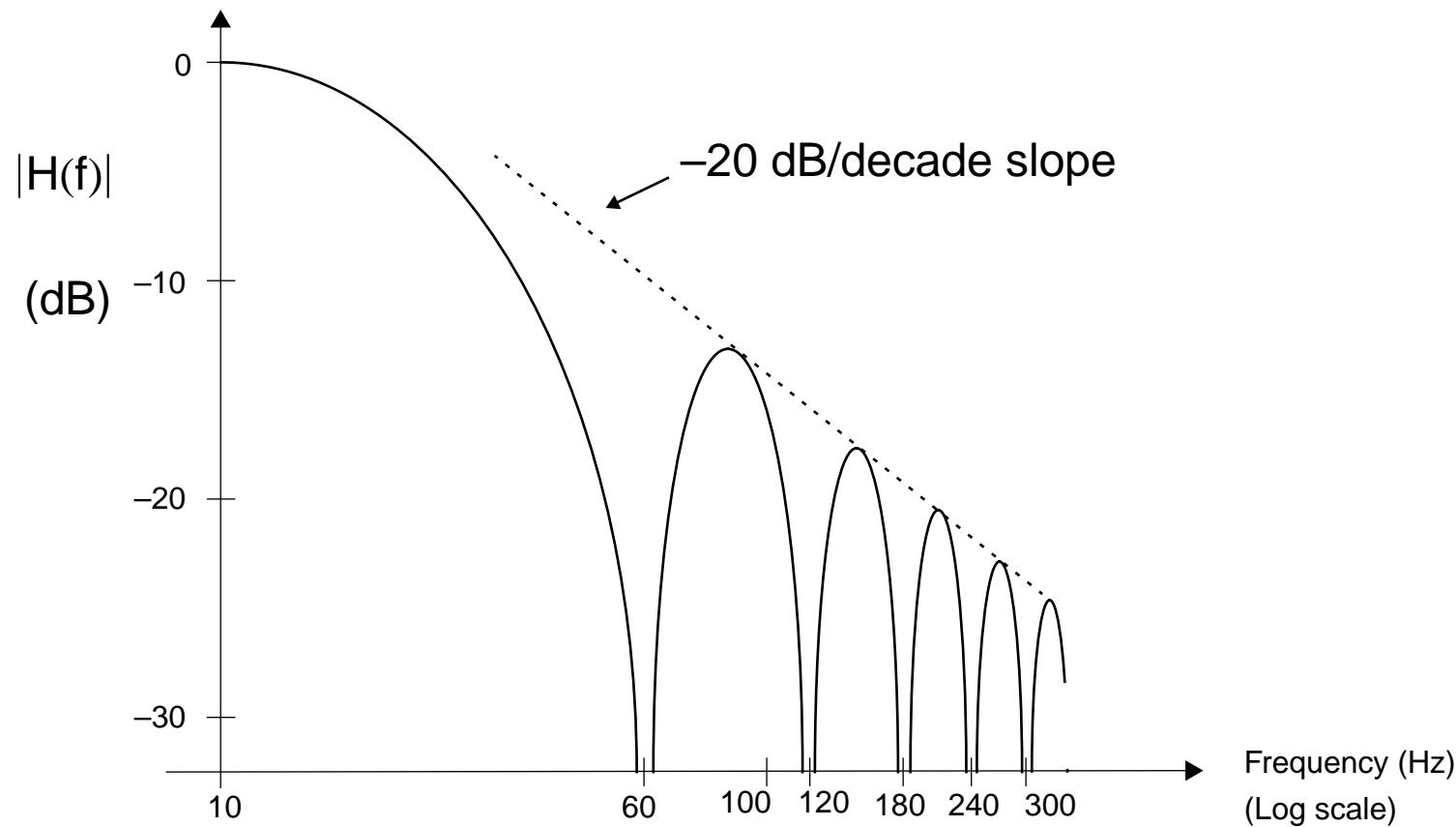


- Count at end of  $T_2$  is digital output
- Does not depend on RC time-constant



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# Integrating Converters



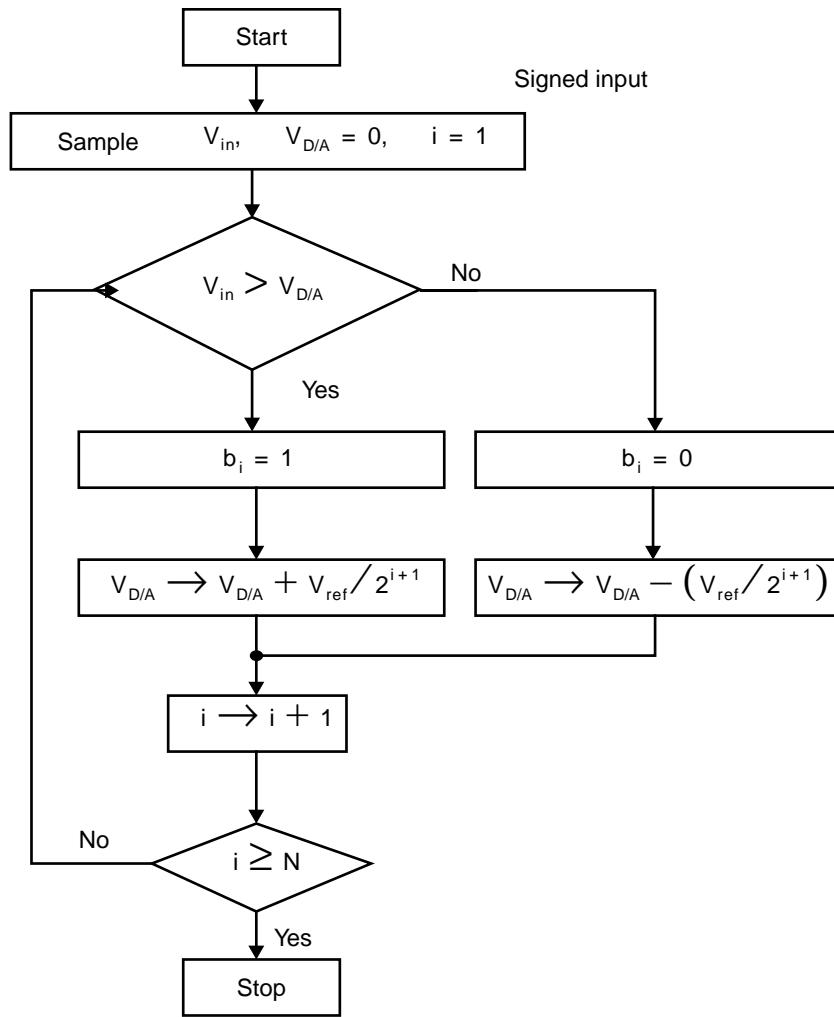
- Notches the input frequencies which are multiples of  $1/T_1$



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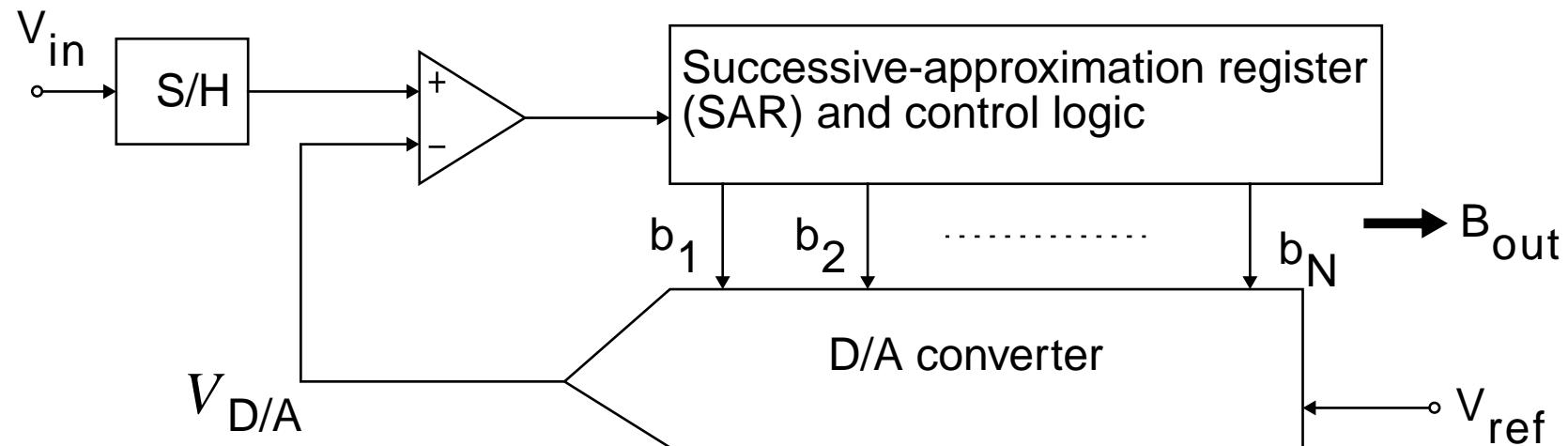
# Successive-Approximation Converters



- Makes use of binary search algorithm
- Requires  $N$  steps for  $N$ -bit converter
- Successively “tunes” a signal until within 1 LSB of input
- Medium speed
- Moderate accuracy



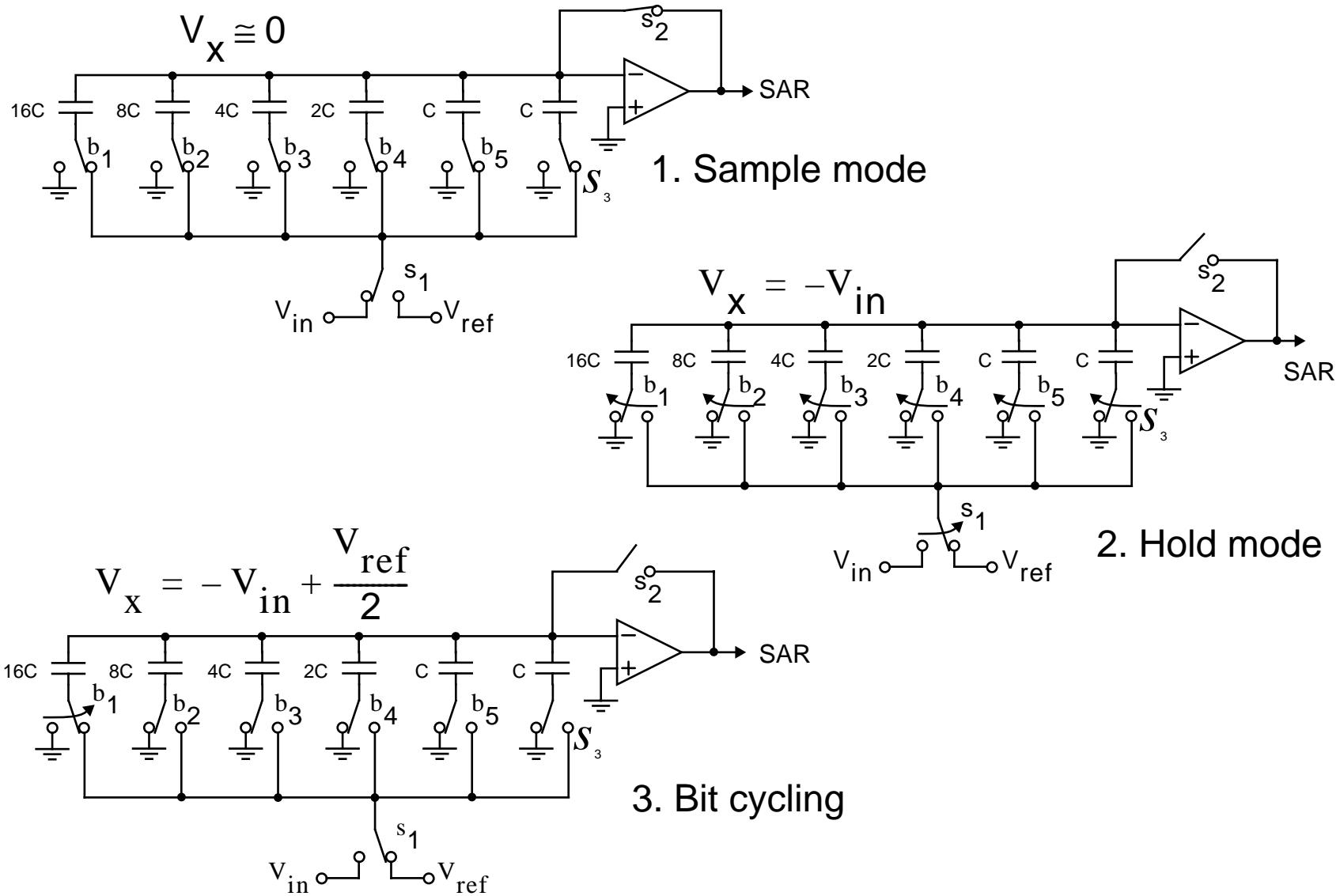
# DAC Based Successive-Approximation



- Adjust  $V_{D/A}$  until within 1 LSB of  $V_{in}$
- Start with MSB and continue until LSB found
- D/A mainly determines overall accuracy
- Input S/H required



# Charge Redistribution A/D



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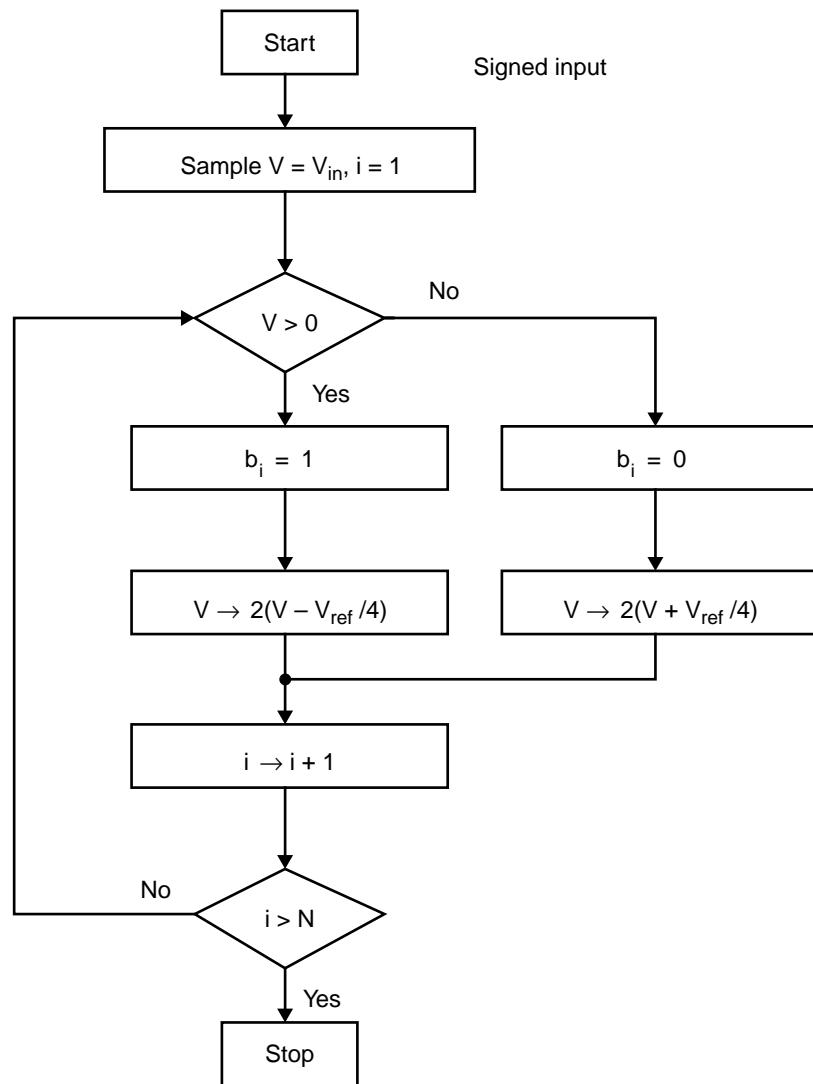
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## Charge Redistribution A/D

- McCreary, 75
- Combines S/H, D/A converter, and difference circuit
- *Sample mode*: Caps charged to  $V_{in}$ , compar reset.
- *Hold mode*: Caps switched to gnd so  $V_x = -V_{in}$
- *Bit cycling*: Cap switched to  $V_{ref}$ . If  $V_x < 0$  cap left connected to  $V_{ref}$  and bit=1. Otherwise, cap back to gnd and bit=0. Repeat  $N$  times
- Cap *bottom plates* connected to  $V_{ref}$  side to minimize parasitic capacitance at  $V_x$ . Parasitic cap does not cause conversion errors but it attenuates  $V_x$ .



# Algorithmic (or Cyclic) A/D Converter



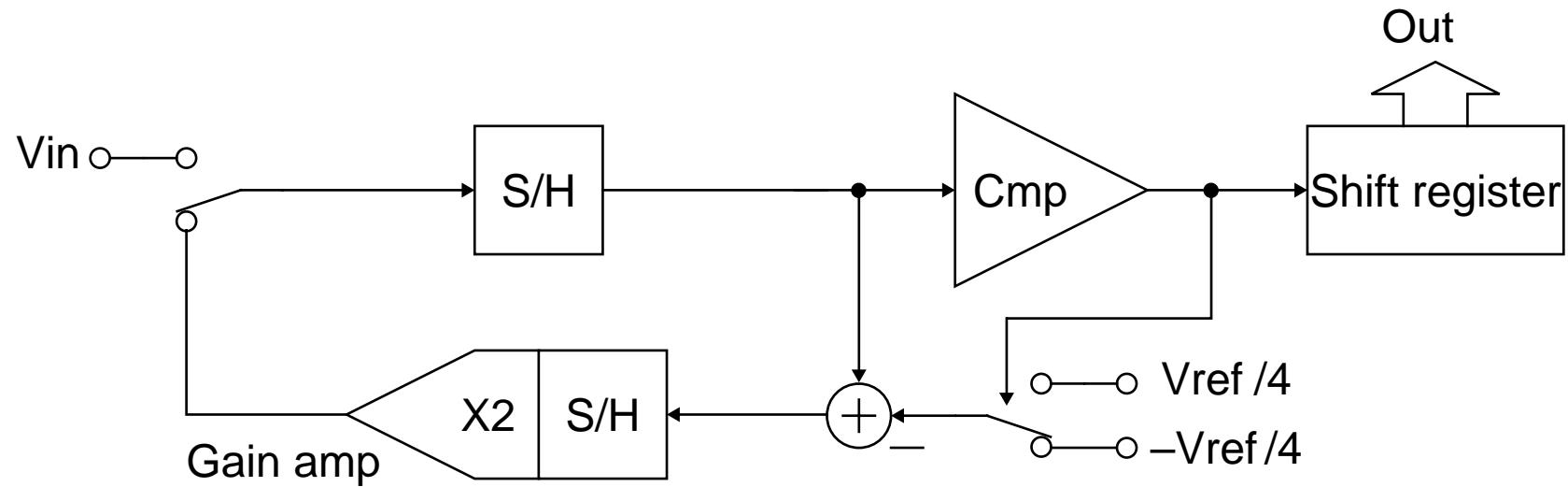
- Operates similar to successive-approx converter
- Successive-approx halves ref voltage each cycle
- Algorithmic doubles error each cycle (leaving ref voltage unchanged)



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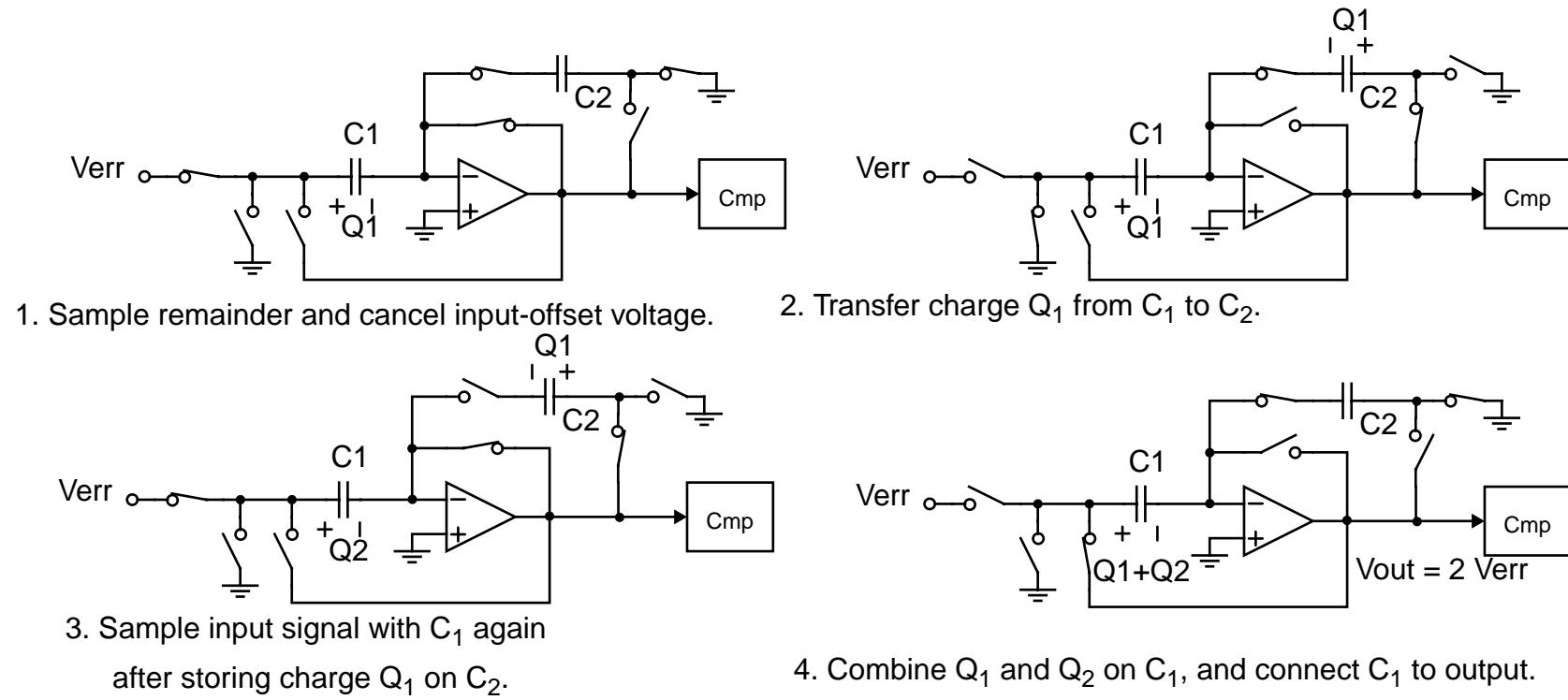
# Ratio-Independent Algorithmic Converter



- McCharles, 77; Li, 84
- Small amount of circuitry — reuse cyclically in time
- Requires a high-precision multiply by 2 gain stage



# Ratio-Independent Algorithmic Converter

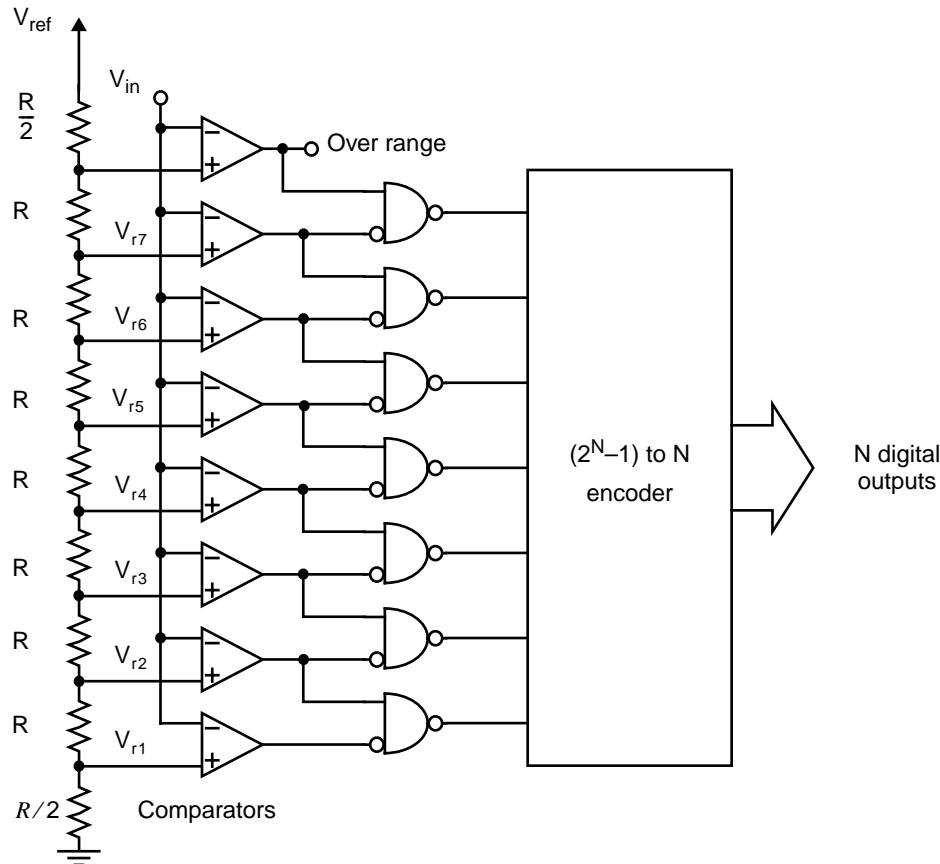


- Does not rely on cap matching
- Sample input twice using  $C_1$ ; hold first charge in  $C_2$  and re-combine with first charge on  $C_1$



# Flash (or Parallel) Converters

- Peetz, 86; Yoshii, 87; Hotta, 87; and Gendai, 91



- High-speed
- Large size and power hungry
- $2^N$  comparators
- Speed bottleneck usually large cap load at input
- Thermometer code out of comps
- Nands used for simpler decoding and/or bubble error correction
- Use comp offset cancellation



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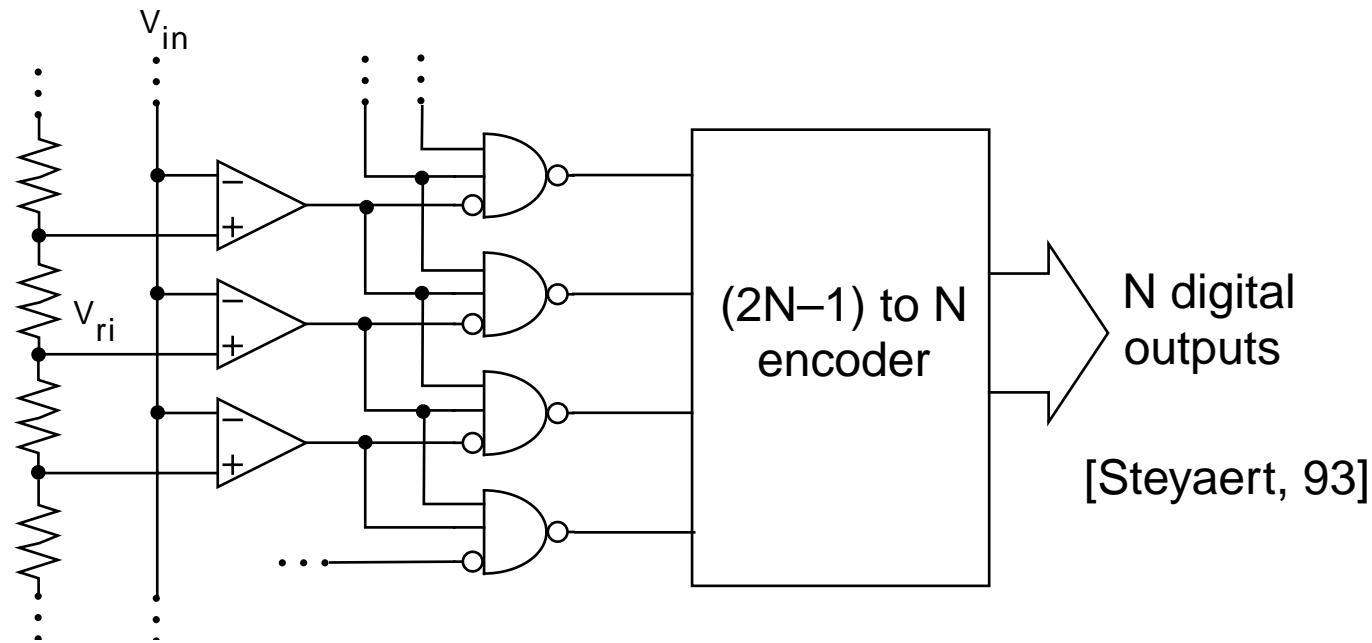
# Issues in Designing Flash A/D Converters

- ***Input Capacitive Loading*** — use interpolating arch.
- ***Resistor-String Bowing*** — Due to  $I_{in}$  of bipolar comps — force center tap (or more) to be correct.
- ***Signal and/or Clock Delay*** — Small arrival diff in clock or input cause errors. (250MHz 8-bit A/D needs 5ps matching for 1LSB) — route clock and  $V_{in}$  together with the delays matched [Gundai, 1991]. Match capacitive loads
- ***Substrate and Power-Supply Noise*** —  $V_{ref} = 2 \text{ V}$  and 8-bit, 7.8 mV of noise causes 1 LSB error — shield clocks and use on-chip supply cap bypass
- ***Flashback*** — Glitch at input due to going from track to latch mode — use preamps in comparators and match input impedances



## Flash Converters — Bubble Errors

- Thermometer code should be 1111110000
- Bubble error (noise, metastability)— 1111110100
- Usually occurs near transition point but can cause **gross errors** depending on encoder



- Can allow errors in lower 2 LSB but have MSBs encoder look at every 4th comp [Gendai, 91]



## Reduced Auto-Zeroing

- Tsukamoto et al, ISSCC/96
- Spalding et al, ISSCC/96
- Reduce the auto-zero portion of conversion
  - auto zero when not performing conversion
  - add one more comparator and ripple up auto-zero

### Advantages

- **Lower power** — less current drawn from ref string
- **More speed** — more time for conversion

### Disadvantage

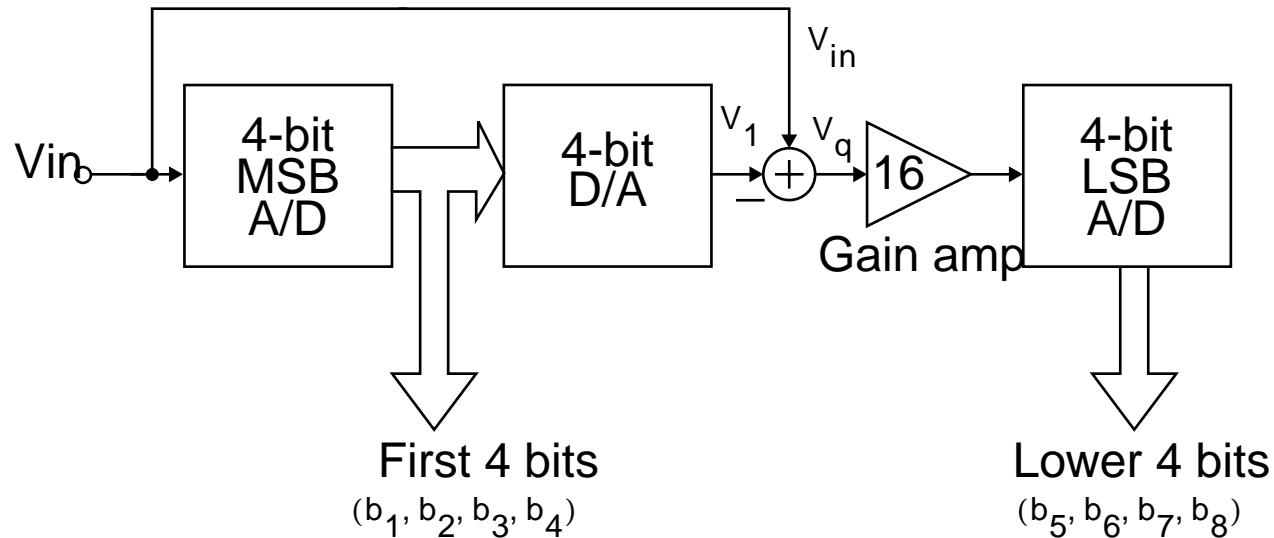
- 1/f noise not rejected as much



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## Two-Step A/D Converters



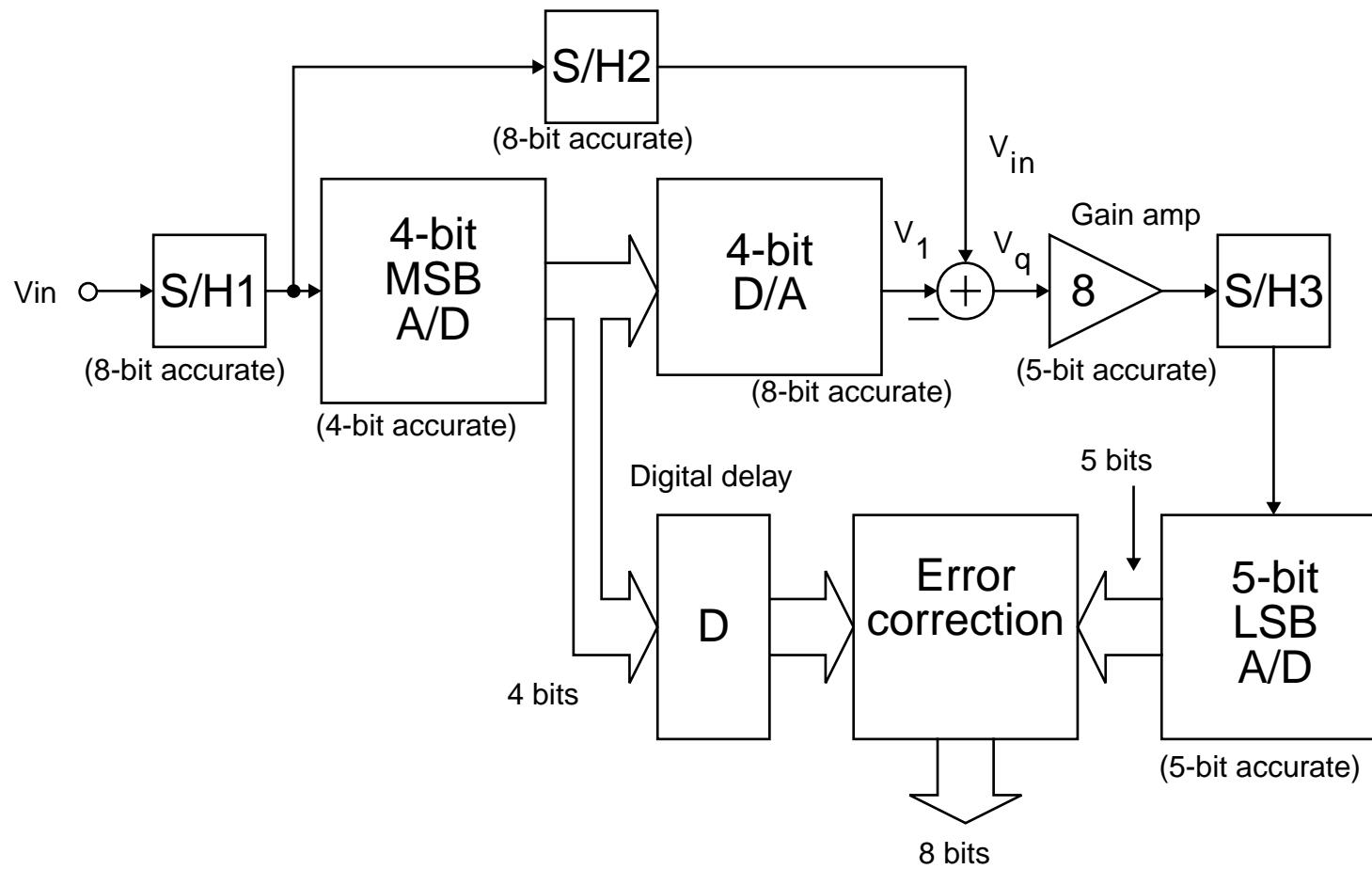
- High-speed, medium accuracy (but 1 sample latency)
- Less area and power than flash
- Only 32 comparators in above 8-bit two-step
- Gain amp likely sets speed limit
- Without digital error correction, many blocks need at least 8-bit accuracy



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# Digital Error Correction

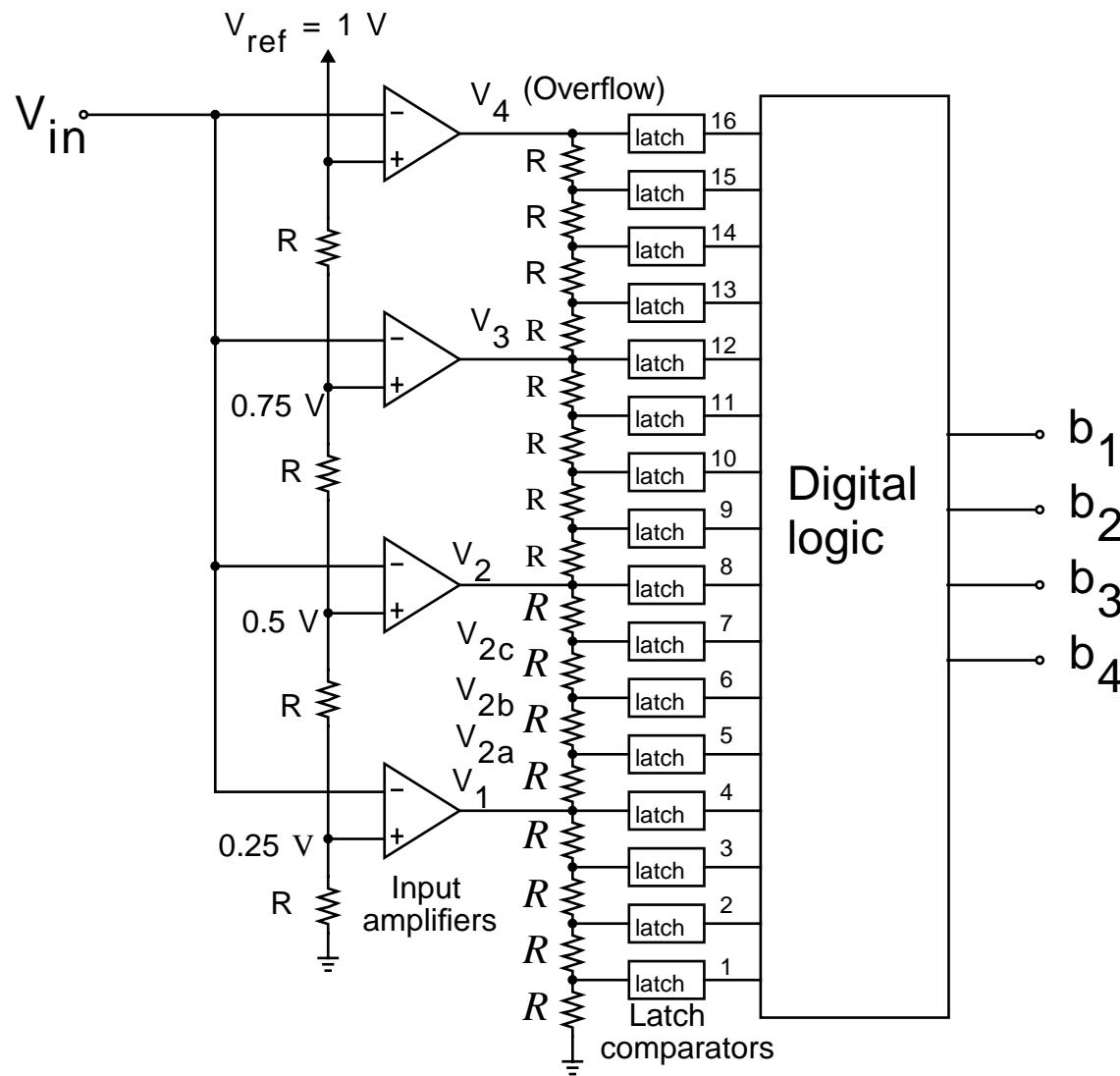


- Relaxes requirements on input A/D
- Requires a 5-bit 2nd stage since  $V_q$  increased
- Example, see [Petschacher, 1990].



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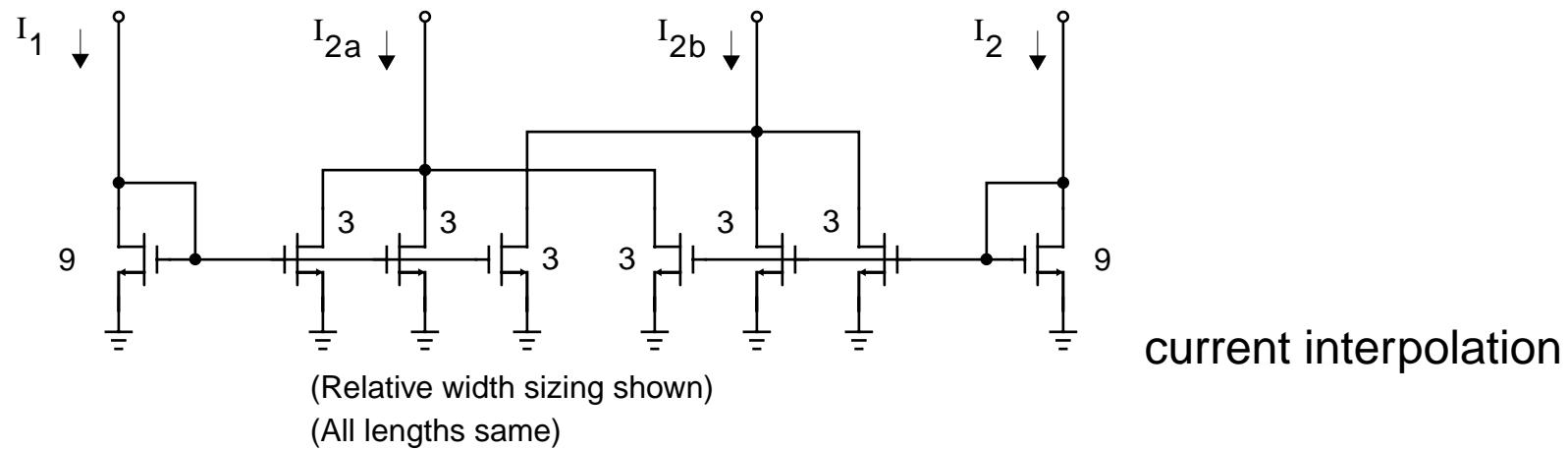
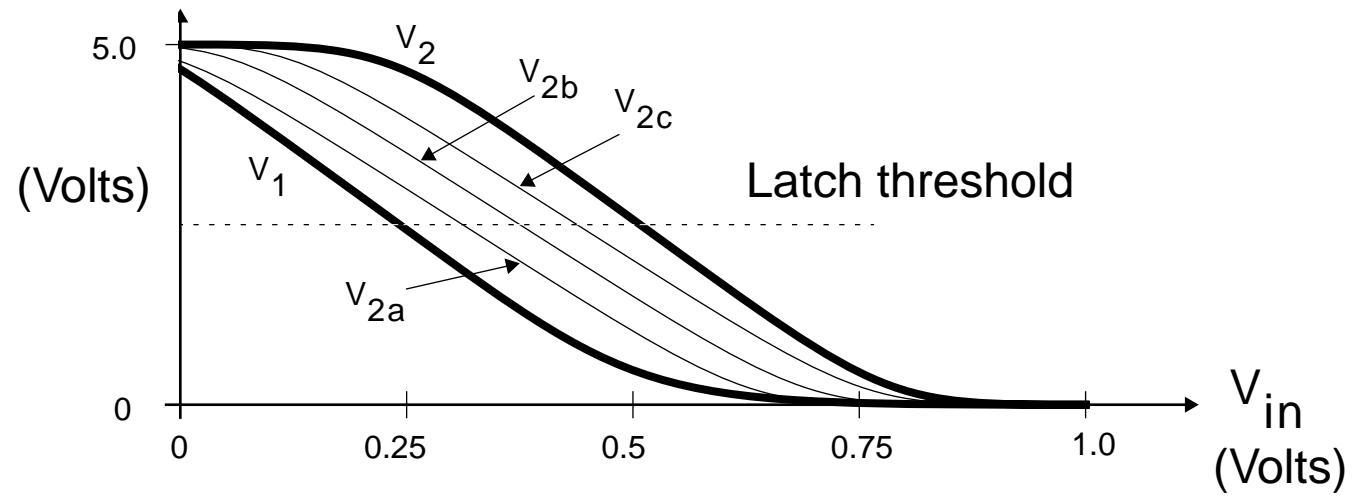
# Interpolating A/D Converters



- Goodenough, 1989
- Steyaert, 1993
- Kusumoto, 1993
- Use input amps to amplify input around reference voltages
- Latch thresholds less critical
- Less cap on input (faster than flash)
- Match delays to latches
- Often combined with folding architecture



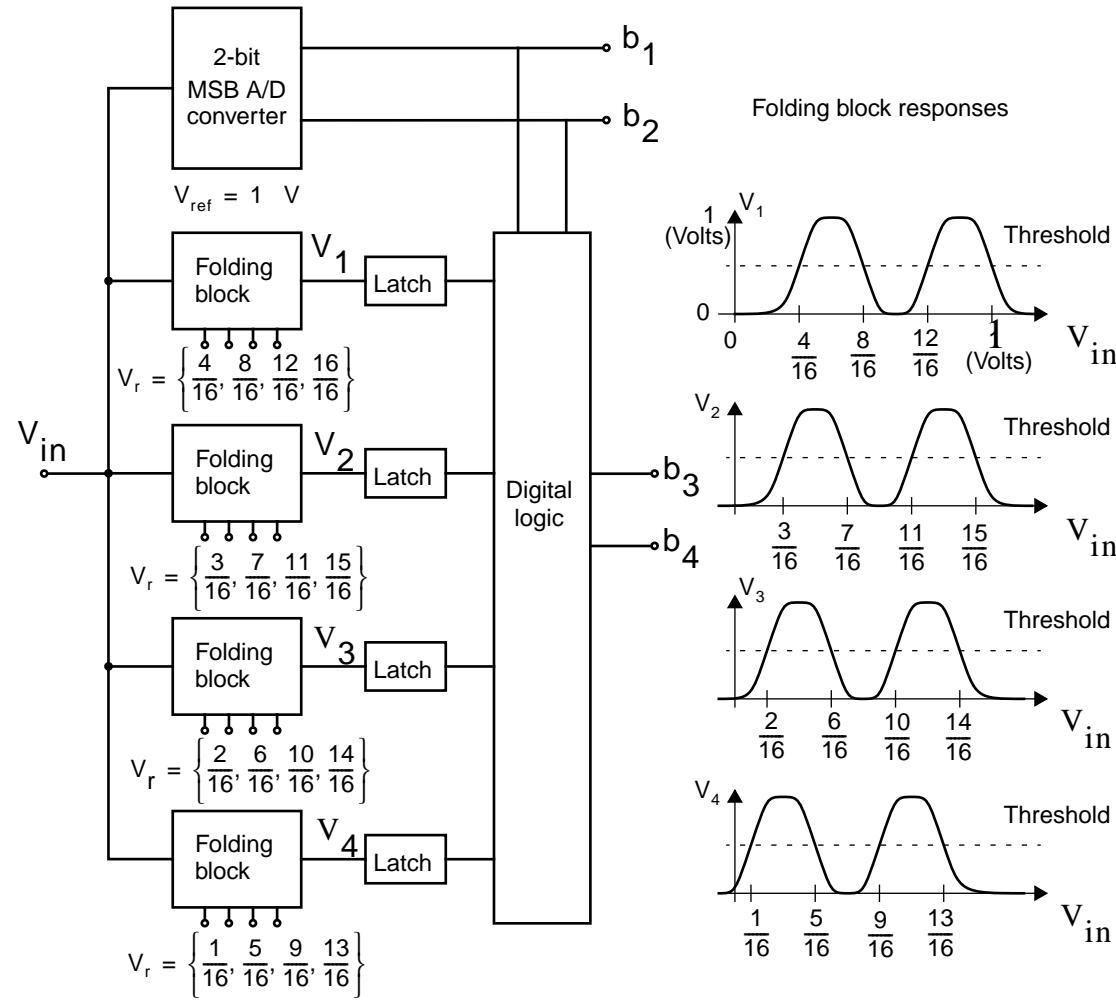
# Interpolating Converters



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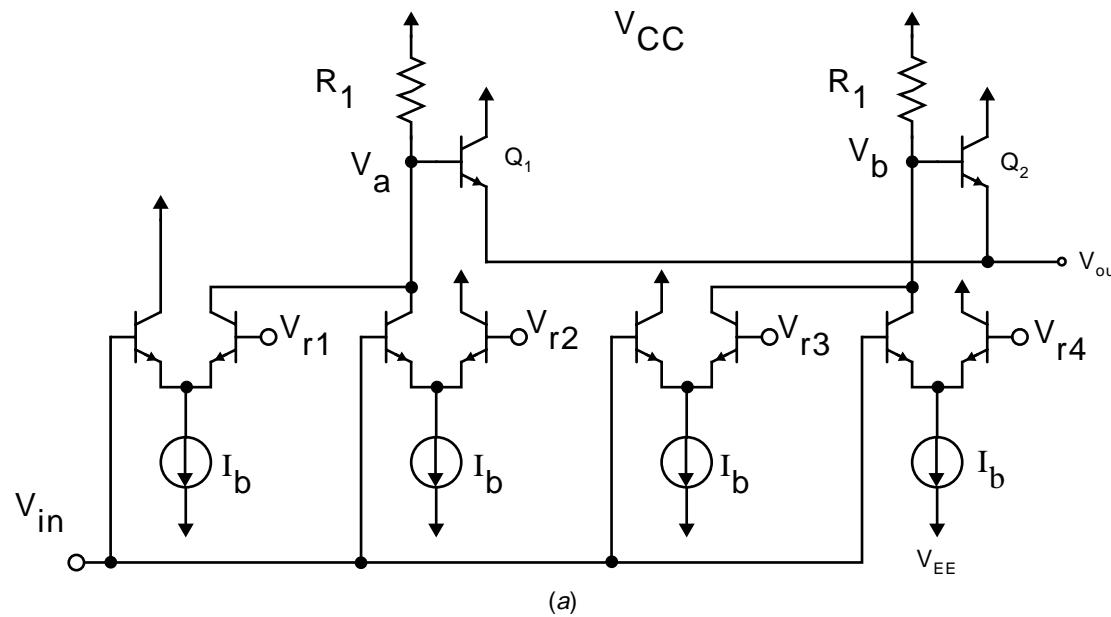
# Folding A/D Converters



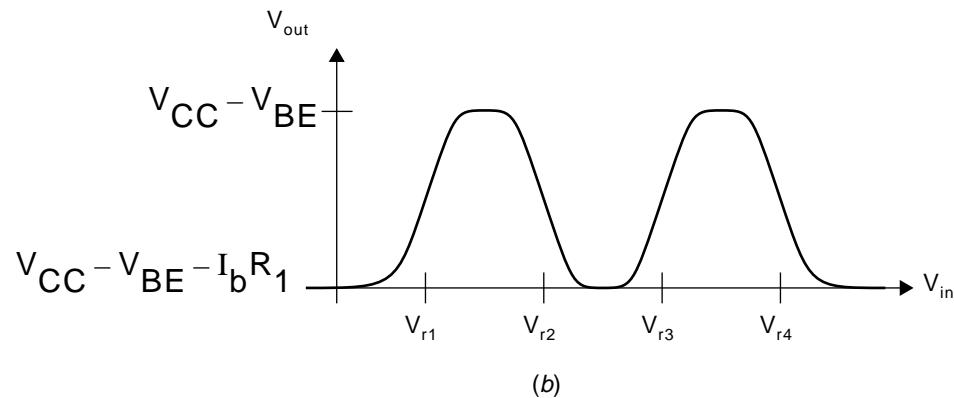
- Reduce number of latches using folding
- Save power and area
- Similar concept to 2-step
- Folding rate of 4 shown for 4 bit converter



# Folding Circuit



(a)



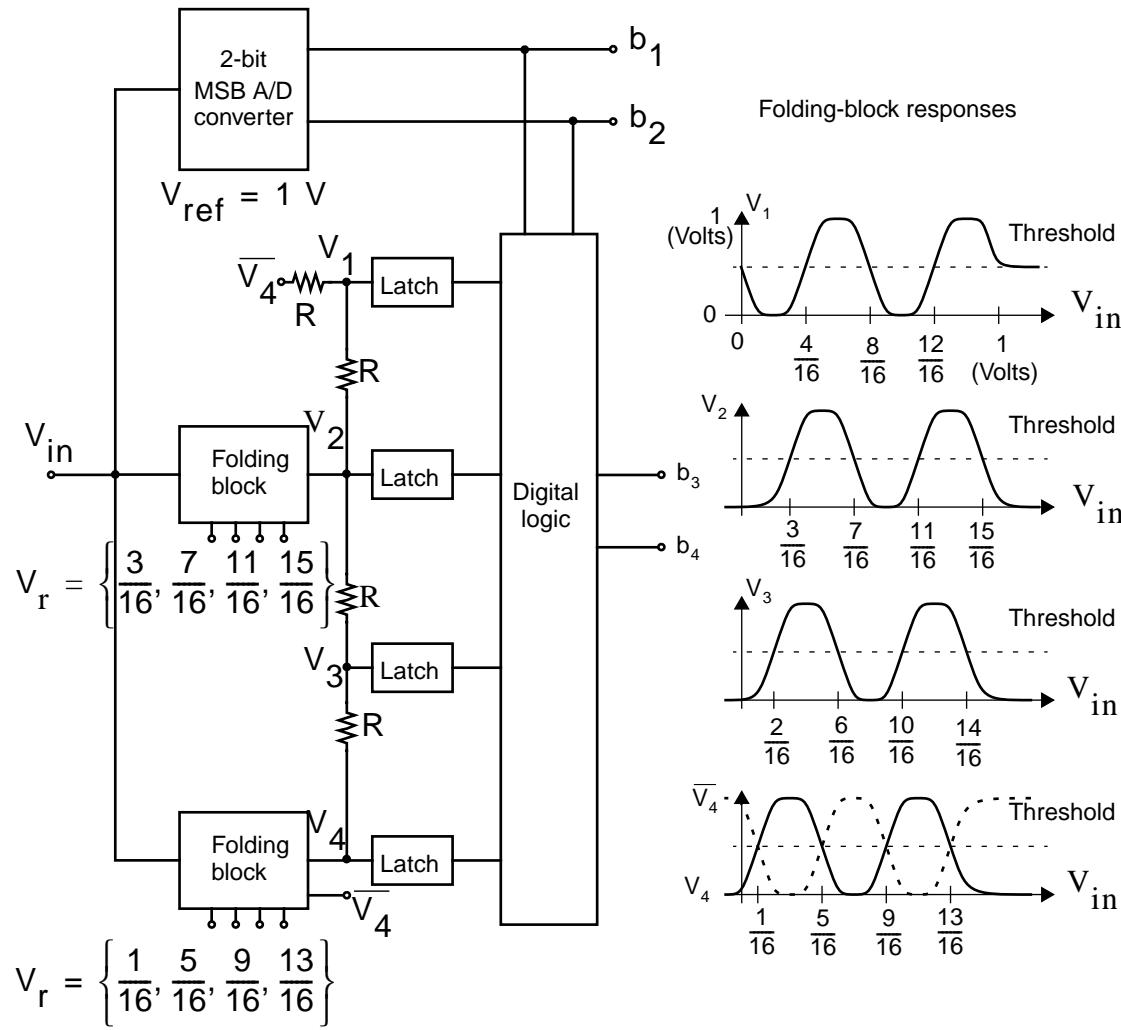
(b)



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# Folding with Interpolation



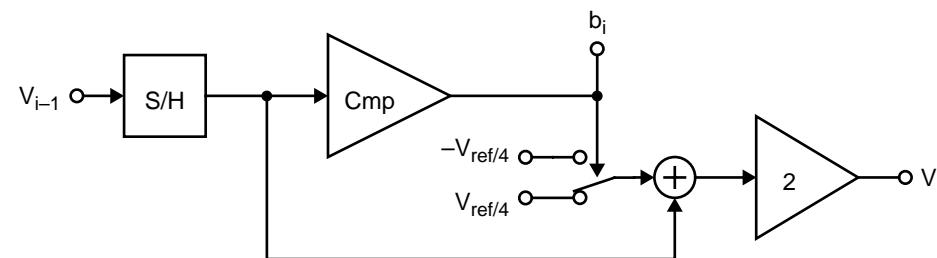
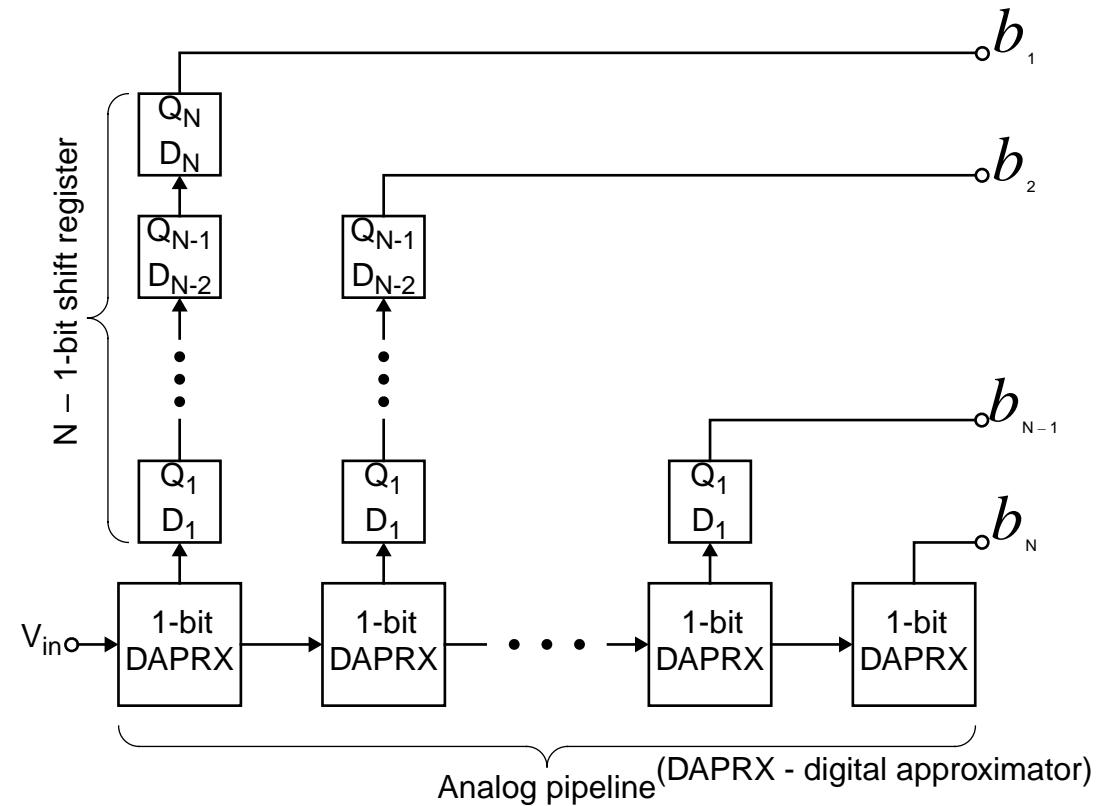
- Folding usually used with interpolation
- Reduces input cap (
- Without interp, same input cap as flash
- [van Valburg, 1992]
- [van de Grift, 1987]
- [Colleran, 1993]



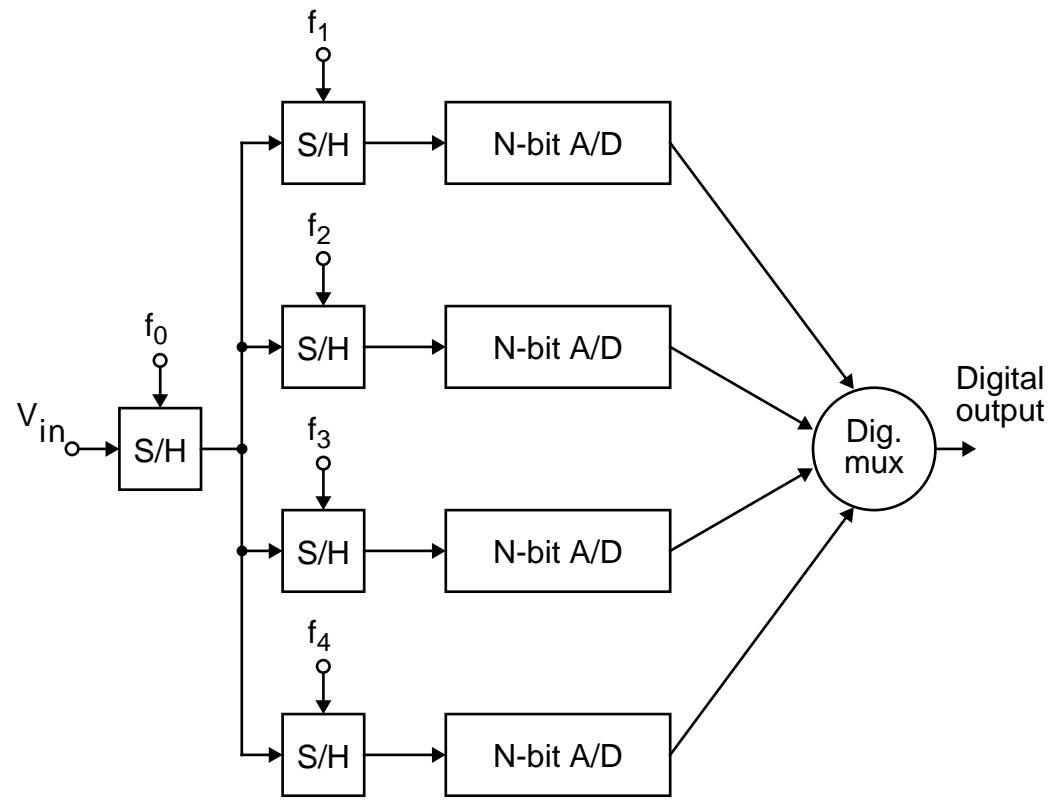
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# Pipelined A/D Converters



# Time-Interleaved A/D Converters [Black, 80]



- Use parallel A/Ds and multiplex them
- Tone occurs at  $fs/N$  for  $N$  converters if mismatched
- Input S/H critical, others not — perhaps different tech for input S/H



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